JJMICROELECTRONICS

100V, 75A, 7.3mΩ N-channel Power SGT MOSFET JMSH1010PG

Features

- Excellent $R_{\text{DS}(\text{ON})}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant

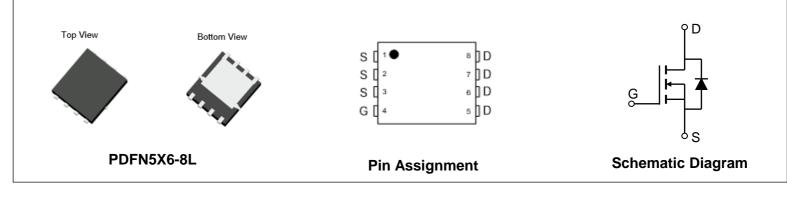
Applications

- Load Switch
- PWM Application
- Power Management

Product Summary

Parameters	Value	Unit
V _{DSS}	100	V
V _{GS(th)_Typ}	2.9	V
I _D (@V _{GS} =10V)	75	А
R _{DS(ON)_Typ} (@V _{GS} =10V	7.3	mΩ





Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1010PG	SH1010P	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ $T_c = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter		Value	Unit
V _{DS}	Drain-to-Source Voltage		100	V
V_{GS}	Gate-to-Source Voltage		±20	V
1-	Continuous Drain Current	$T_{\rm C} = 25^{\circ}{\rm C}$	75	А
Ι _D	Commuous Drain Current	$T_{\rm C} = 100^{\circ}{\rm C}$	47	A
I _{DM}	Pulsed Drain Current ⁽¹⁾		Refer to Fig.4	A
E _{AS}	Single Pulsed Avalanche Energy ⁽²⁾		165	mJ
PD	Power Discipation	$T_{\rm C} = 25^{\circ}{\rm C}$	104	w
' D	Power Dissipation	$T_{c} = 100^{\circ}C$	42	vv
T _J , T _{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Мах	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	45	°C/W
R _{eJC}	Thermal Resistance, Junction to Case	1.2	C/VV

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics					ļ
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics	-•				,
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0	2.9	3.8	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_{D} = 20A$	-	7.3	9.5	mΩ
Dynam	ic Characteristics			•		
R_g	Gate Resistance	f = 1MHz	-	1.7	-	Ω
C _{iss}	Input Capacitance		1095	1532	2069	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	459	643	868	pF
C _{rss}	Reverse Transfer Capacitance		15	21	28	pF
Qg	Total Gate Charge		19	27	36	nC
Q _{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_D = 20A$	-	7.6	10.2	nC
Q_{gd}	Gate Drain("Miller") Charge	$V_{\rm DS} = 300$, $V_{\rm D} = 20$ A	-	8.1	10.9	nC
Switchi	ing Characteristics					
t _{d(on)}	Turn-On DelayTime		-	11	-	ns
t _r	Turn-On Rise Time	V _{GS} = 10V, V _{DD} = 50V	-	21	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 20A, R_{GEN} = 3\Omega$	-	23	-	ns
t _f	Turn-Off Fall Time		-	8.8	-	ns
Body D	ode Characteristics	- • • • • •			<u>.</u>	
I _S	Maximum Continuous Body Diode Forward Current		-	-	75	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	300	А
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time		32	44	60	ns
Qrr	Body Diode Reverse Recovery Charge	I _F = 20A, di/dt = 100A/us	-	56	-	nC

Electrical Characteristics ($T_J = 25^{\circ}C$ unless otherwise specified)

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

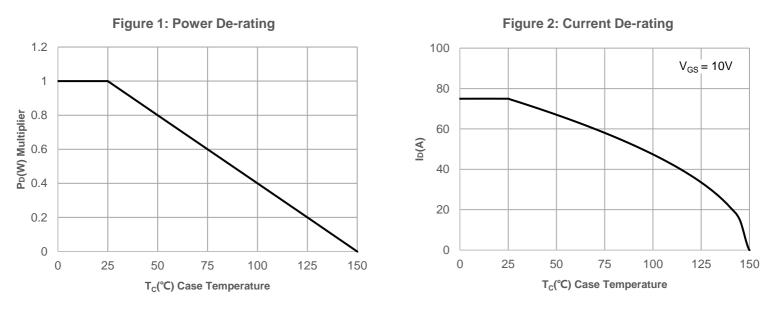
2. E_{AS} condition: Starting T_J =25C, V_{DD} =50V, V_G =10V, R_G =25ohm, L=3mH, I_{AS} =10.5A, V_{DD} =0V during time in avalanche.

3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.

4. Pulse Test: Pulse Width ${\leqslant}300\mu\text{s},$ Duty Cycle ${\leqslant}0.5\%.$







Typical Performance Characteristics



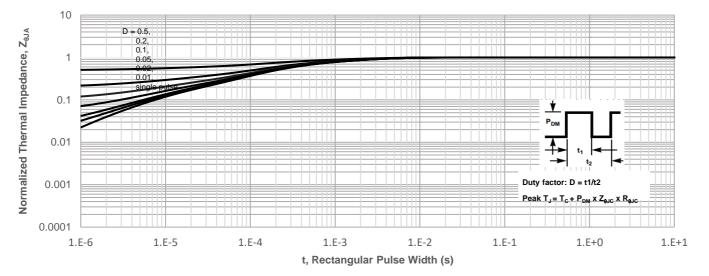
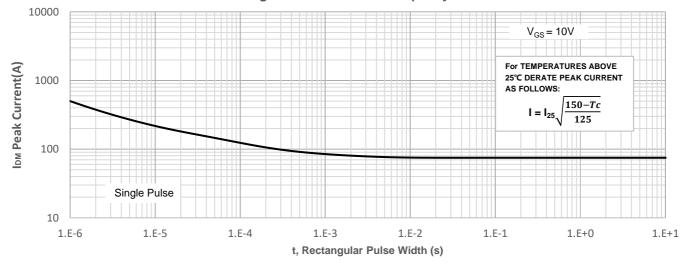
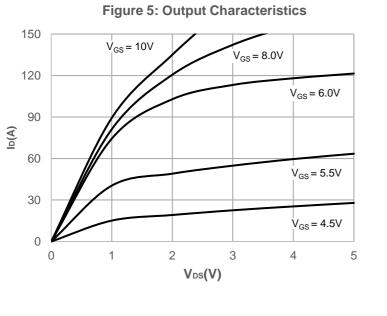


Figure 4: Peak Current Capacity







Typical Performance Characteristics



 $V_{DS} = 5V$

20

100

10

Is(A)

 $V_{GS} = 0V$

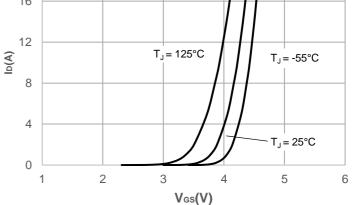


Figure 8: Body Diode Characteristics

Figure 6: Typical Transfer Characteristics

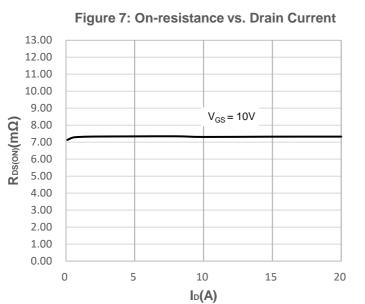
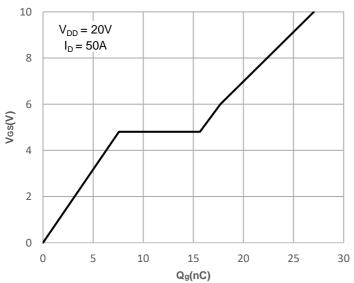
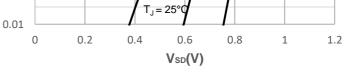
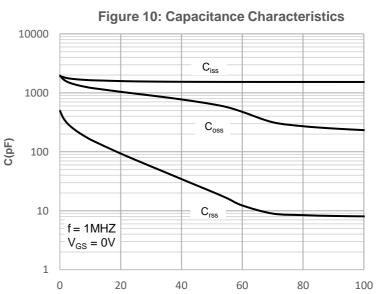


Figure 9: Gate Charge Characteristics



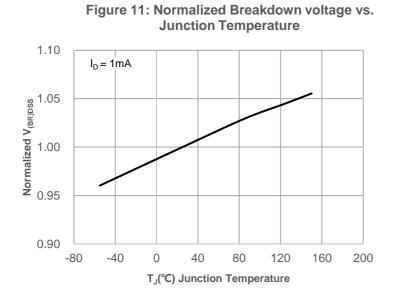
1 T_J = 125°C T_J = -55°C 0.1



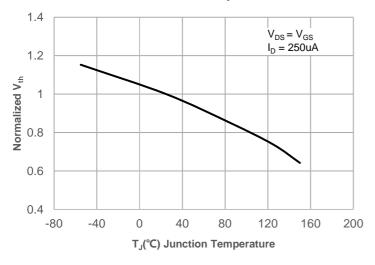


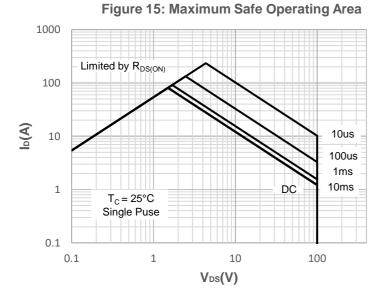
VDS(V)

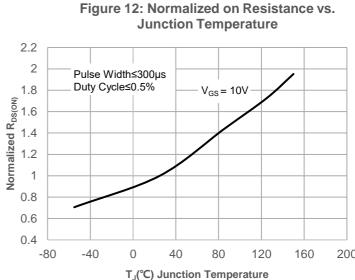


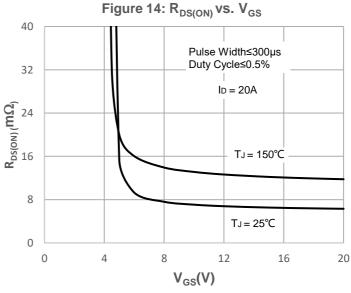


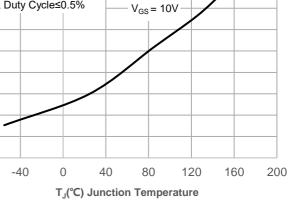


















Test Circuit

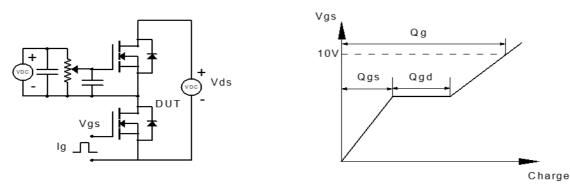


Figure 1: Gate Charge Test Circuit & Waveform

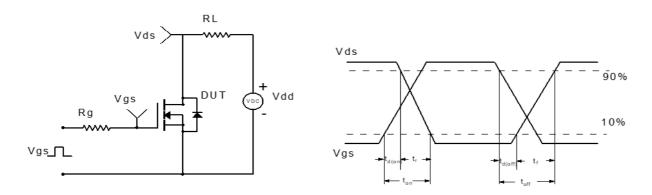


Figure 2: Resistive Switching Test Circuit & Waveform

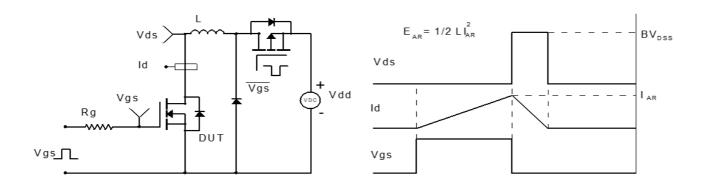


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

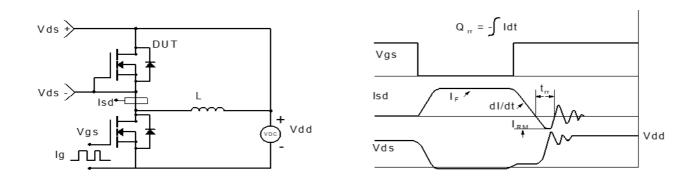
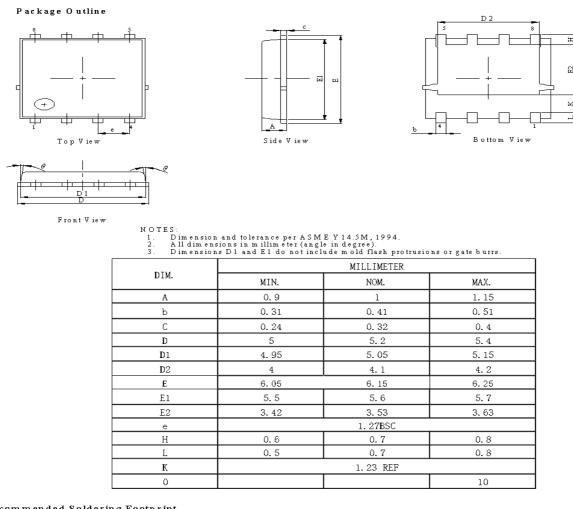


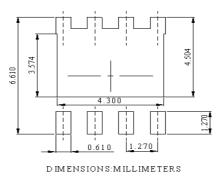
Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data(PDFN5X6-8L)



Recommended Soldering Footprint



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